SemiHow
Know-How for Semiconductor

August 2012

BV_{DSS} = 600 V

$R_{DS(on)\ typ}$ = 0.96 Ω

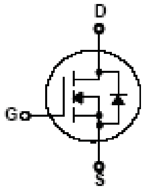
I_D = 7.5 A

HFS8N60U

600V N-Channel MOSFET

TO-220F

1.Gate 2. Drain 3. Source



FEATURES

☐ Originative New Design
☐ Superior Avalanche Rugged Technology
☐ Robust Gate Oxide Technology
☐ Very Low Intrinsic Capacitances
☐ Excellent Switching Characteristics
☐ Unrivalled Gate Charge : 22.0 nC (Typ.)
☐ Extended Safe Operating Area
☐ Lower $R_{DS(ON)}$: 0.96 Ω (Typ.) @V_{GS}=10V
☐ 100% Avalanche Tested

Absolute Maximum Ratings

T_C=25℃ unless otherwise specified

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	600	V
I_D	Drain Current – Continuous (T_C = 25℃)	7.5 *	A
	Drain Current – Continuous (T_C = 100℃)	4.7 *	A
I_{DM}	Drain Current – Pulsed (Note 1)	30.0 *	A
V_{GS}	Gate-Source Voltage	±30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	280	mJ
I_{AR}	Avalanche Current (Note 1)	7.5	A
E_{AR}	Repetitive Avalanche Energy (Note 1)	4.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Power Dissipation (T_C = 25℃)	48	W
	- Derate above 25℃	0.38	W/℃
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	℃
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	℃

* Drain current limited by maximum junction temperature

Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	2.6	℃/W
$R_{\theta JA}$	Junction-to-Ambient	--	62.5	

Package Marking and Odering Information

Device Marking	Week Marking	Package	Packing	Quantity	RoHS Status
HFS8N60U	YWWX	TO-220F(A)	Tube	50	Pb Free
HFS8N60US	YWWX	TO-220F(B)	Tube	50	Pb Free
HFS8N60U	YWWXg	TO-220F(A)	Tube	50	Halogen Free
HFS8N60US	YWWXg	TO-220F(B)	Tube	50	Halogen Free

※ TO-220F(A) : Dual Gauge, TO-220F(B) : Single Gauge

Electrical Characteristics T_C=25 °C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units

On Characteristics

V_{GS}	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 ㎂	2.5	--	4.5	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 3.75 A	--	0.96	1.2	Ω

Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 ㎂	600	--	--	V
ΔBV_{DSS} /ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 ㎂, Referenced to 25℃	--	0.6	--	V/℃
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 600 V, V_{GS} = 0 V	--	--	1	㎂
		V_{DS} = 480 V, T_C = 125℃	--	--	10	㎂
I_{GSS}	Gate-Body Leakage Current	V_{GS} = ±30 V, V_{DS} = 0 V	--	--	±100	㎁

Dynamic Characteristics

C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	--	1200	1560	㎊
C_{oss}	Output Capacitance		--	100	130	㎊
C_{rss}	Reverse Transfer Capacitance		--	11.0	14.5	㎊

Switching Characteristics

$t_{d(on)}$	Turn-On Time	V_{DS} = 300 V, I_D = 7.5 A, R_G = 25 Ω (Note 4,5)	--	35	70	㎱
t_r	Turn-On Rise Time		--	50	100	㎱
$t_{d(off)}$	Turn-Off Delay Time		--	120	240	㎱
t_f	Turn-Off Fall Time		--	50	100	㎱
Q_g	Total Gate Charge	V_{DS} = 480 V, I_D = 7.5 A, V_{GS} = 10 V (Note 4,5)	--	22.0	29.0	nC
Q_{gs}	Gate-Source Charge		--	6.5	--	nC
Q_{gd}	Gate-Drain Charge		--	6.5	--	nC

Source-Drain Diode Maximum Ratings and Characteristics

I_S	Continuous Source-Drain Diode Forward Current		--	--	7.5	A
I_{SM}	Pulsed Source-Drain Diode Forward Current		--	--	30	
V_{SD}	Source-Drain Diode Forward Voltage	I_S = 7.5 A, V_{GS} = 0 V	--	--	1.4	V
trr	Reverse Recovery Time	I_S = 7.5 A, V_{GS} = 0 V di_F/dt = 100 A/μs (Note 4)	--	350	--	㎱
Qrr	Reverse Recovery Charge		--	3.3	--	μC

Notes ;

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L=9.0mH, I_{AS}=7.5A, V_{DD}=50V, R_G=25Ω, Starting T_J =25°C
3. I_{SD}≤7.5A, di/dt≤200A/μs, V_{DD}≤BV_{DSS} , Starting T_J =25 °C
4. Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%
5. Essentially Independent of Operating Temperature

Typical Characteristics

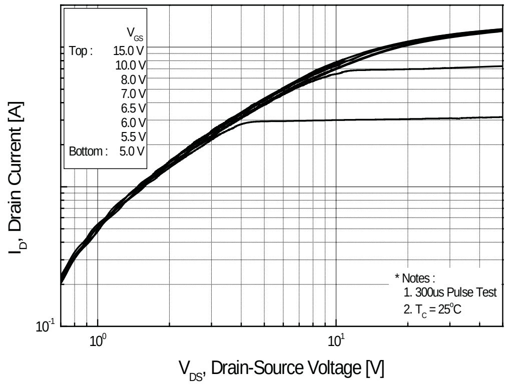


Figure 1. On Region Characteristics

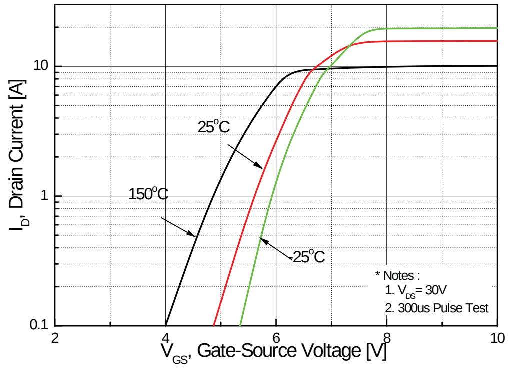


Figure 2. Transfer Characteristics

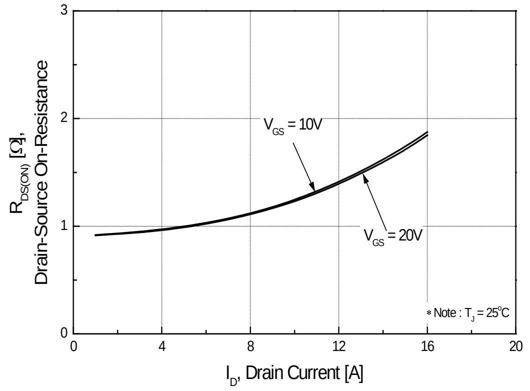


Figure 3. On Resistance Variation vs Drain Current and Gate Voltage

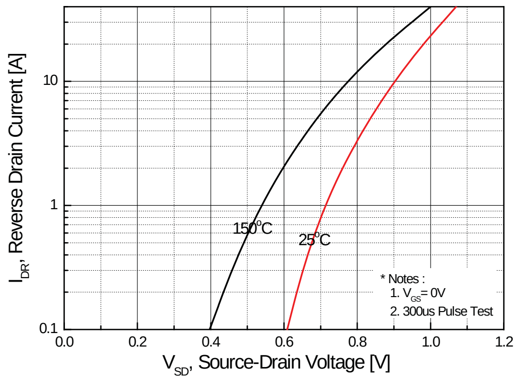


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

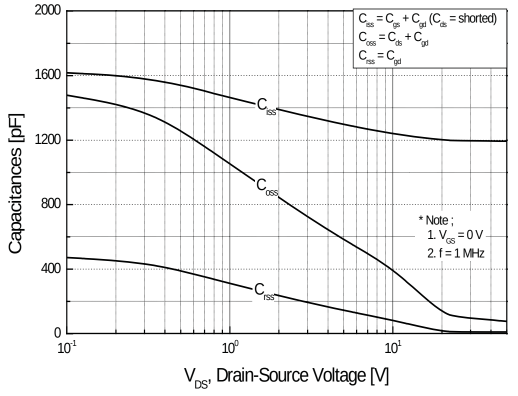


Figure 5. Capacitance Characteristics

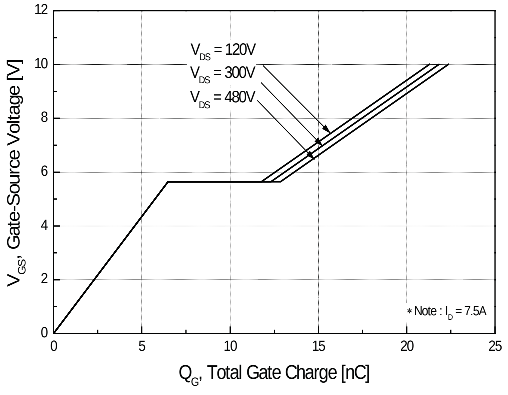


Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

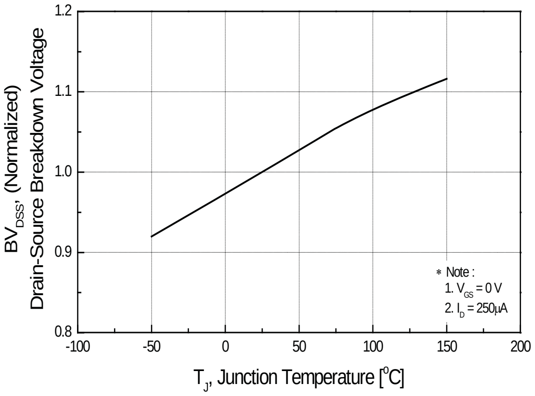


Figure 7. Breakdown Voltage Variation vs Temperature

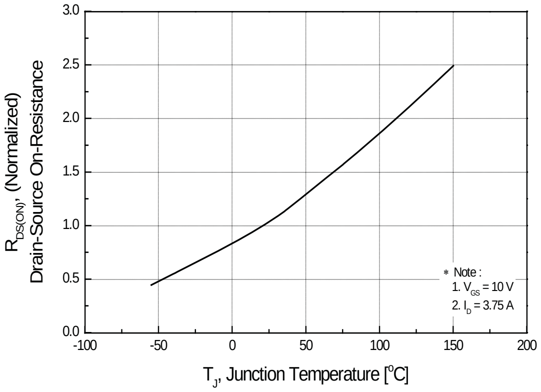


Figure 8. On-Resistance Variation vs Temperature

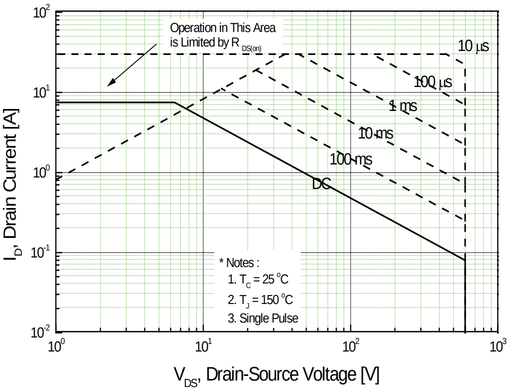


Figure 9. Maximum Safe Operating Area

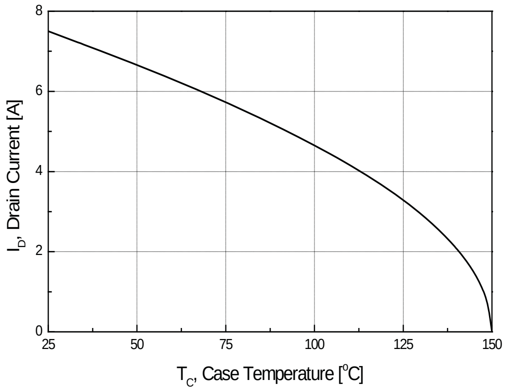


Figure 10. Maximum Drain Current vs Case Temperature

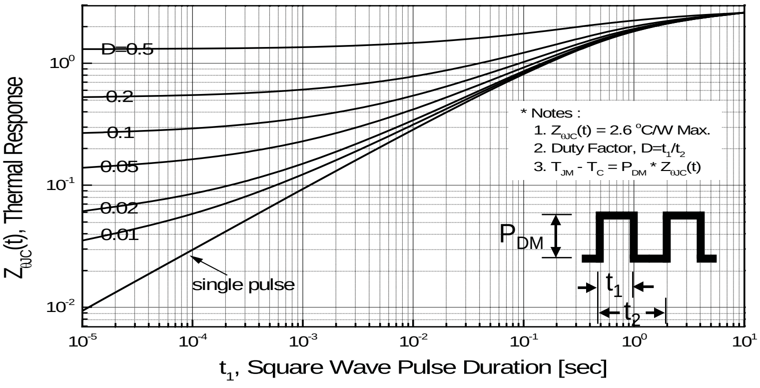


Figure 11. Transient Thermal Response Curve

Fig 12. Gate Charge Test Circuit & Waveform

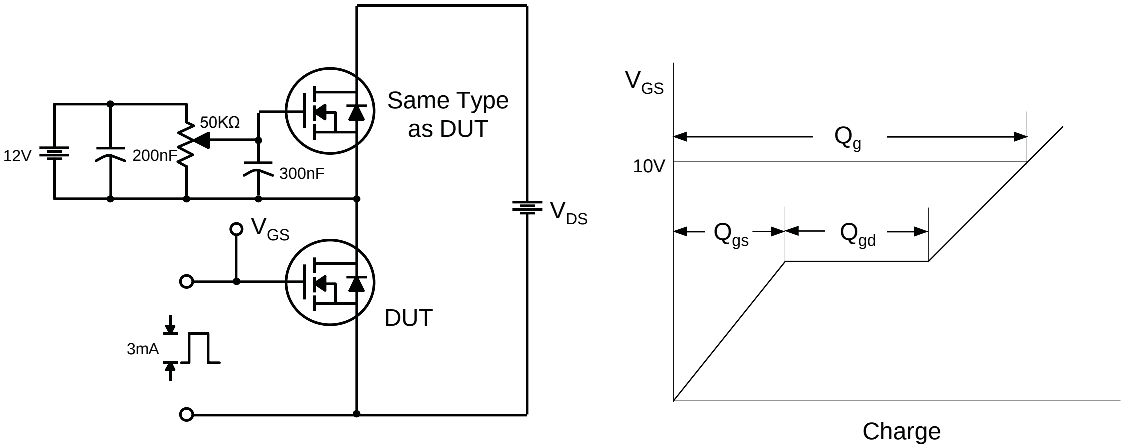


Fig 13. Resistive Switching Test Circuit & Waveforms

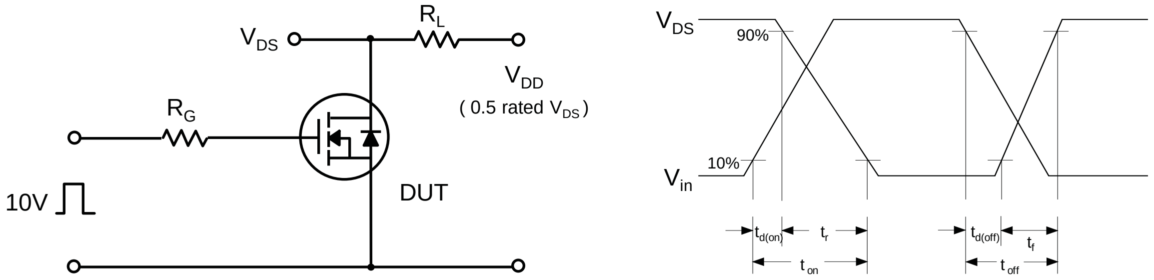
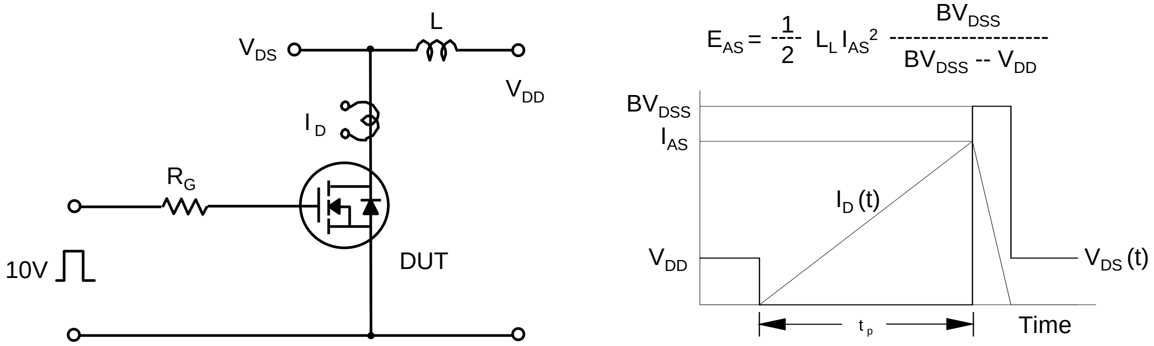
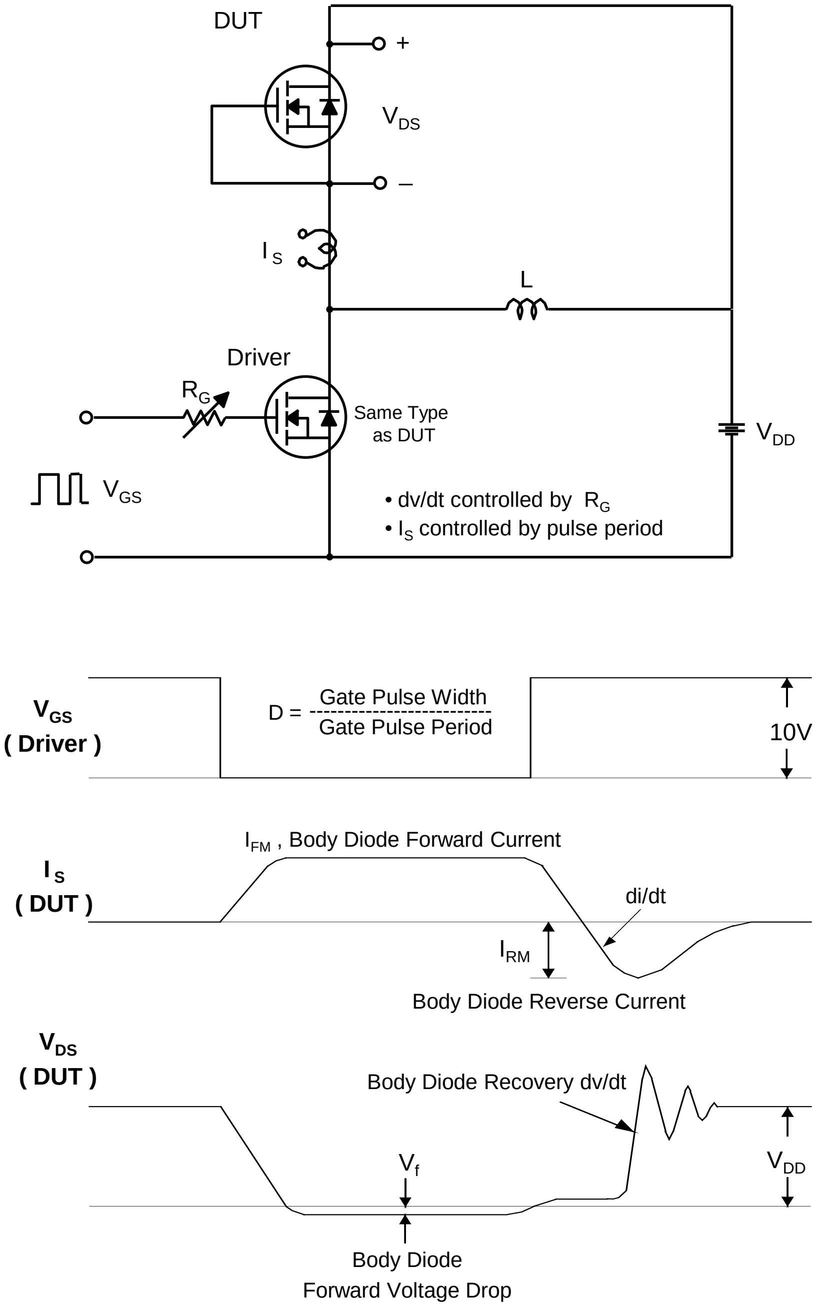


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms



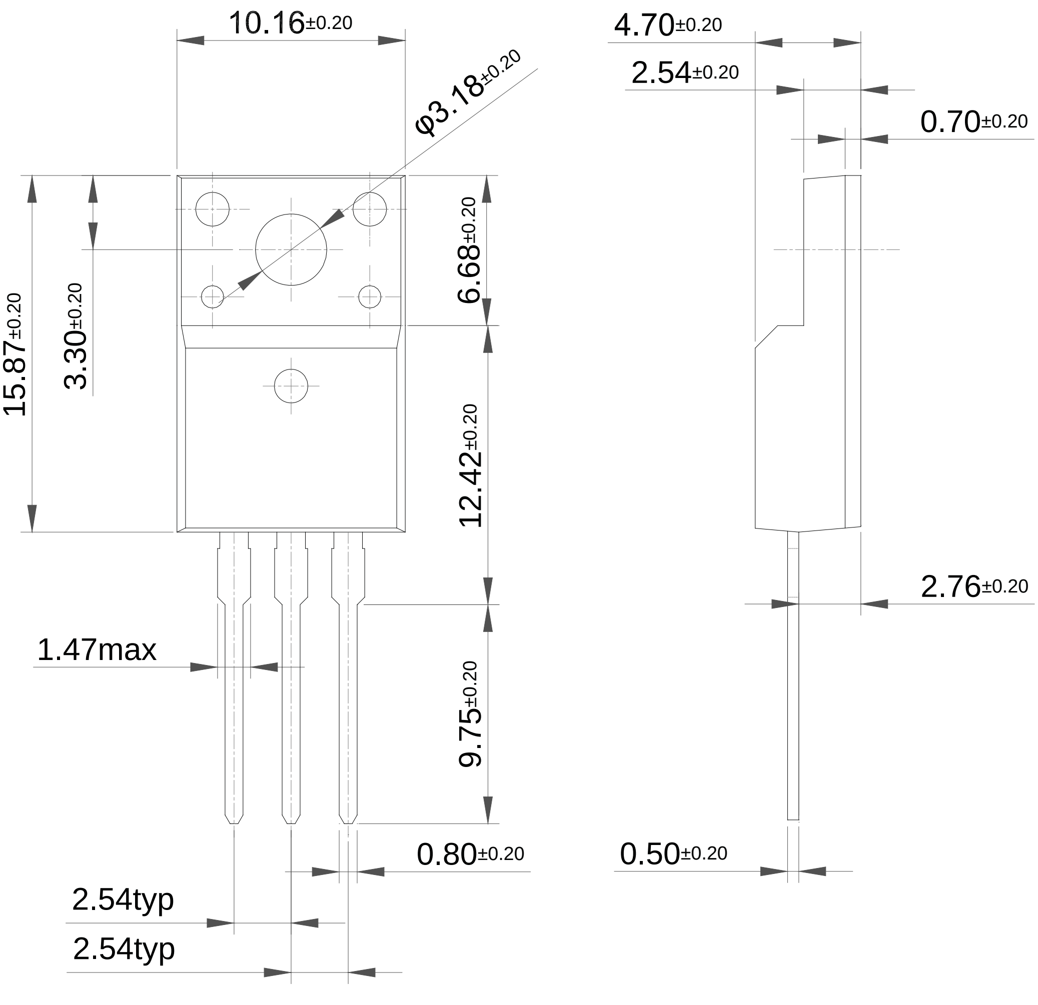
$$E_{AS} = \frac{1}{2} L_L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



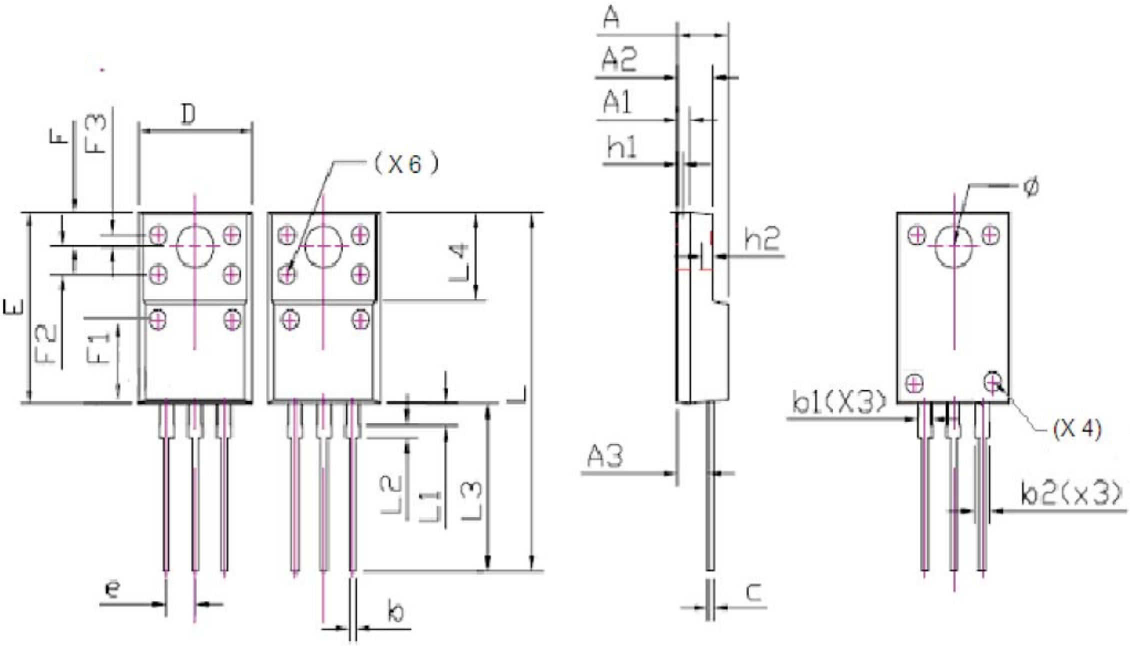
Package Dimension

TO-220F (A)



Package Dimension

TO-220F (B)



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.300	4.700	0.169	0.185
A1	1.300 REF.		0.051 REF.	
A2	2.800	3.300	0.110	0.130
A3	2.500	2.900	0.098	0.114
b	0.500	0.750	0.020	0.030
b1	1.150	1.300	0.045	0.051
b2	1.150	1.400	0.045	0.055
c	0.500	0.750	0.020	0.030
D	9.900	10.360	0.390	0.408
E	14.800	15.200	0.583	0.598
e	2.540 TYP.		0.100 TYP.	
F	2.700 REF.		0.106 REF.	
F1	6.300 REF.		0.248 REF.	
F2	2.200 REF.		0.087 REF.	
F3	0.900 REF.		0.035 REF.	
Φ	3.200	3.500	0.126	0.138
h1	0.500 REF.		0.020 REF.	
h2	0.800 REF.		0.031 REF.	
L	28.000	29.000	1.102	1.142
L1	1.400	1.800	0.055	0.071
L2	1.200	2.000	0.047	0.079
L3	13.0	13.8	0.512	0.543
L4	7.000 REF.		0.276 REF.	